

## Description

The SSM3J358R uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

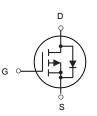
### **General Features**

$$\label{eq:VDS} \begin{split} V_{DS} &= -20 V, I_D = -7 A \\ R_{DS(ON)} &< 26 m \Omega @ V_{GS} {=} 4.5 V \end{split}$$

## Application

High power and current handing capability Lead free product is acquired Surface mount package PWM applications Load switch Power management





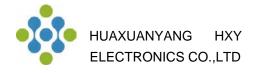
P-Channel MOSFET

## Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
SSM3J358R	SOT-23-3L	HXY MOSFET	3000

## Absolute Maximum Ratings (T<sub>A</sub>=25<sup>°</sup>C unless otherwise noted)

Symbol	Symbol Parameter		Unit	
VDS	Drain-Source Voltage	-20	V	
Vgs	V <sub>GS</sub> Gate-Source Voltage		V	
I <sub>D</sub>	I <sub>D</sub> Drain Current-Continuous       I <sub>DM</sub> Drain Current-Pulsed <sup>(Note 1)</sup>		А	
Ідм			А	
PD	Maximum Power Dissipation	1	W	
Тј,Тѕтб	T <sub>J</sub> ,T <sub>STG</sub> Operating Junction and Storage Temperature Range		°C	
Reja	Reja Thermal Resistance, Junction-to-Ambient (Note 2)		°C/W	



## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-20			V
△BV <sub>DSS</sub> ∕△T」 BVDSS Temperature Coefficient		Reference to $25^{\circ}$ C , I <sub>D</sub> =-1mA		-0.01		V/°C
		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6.5A		20	26	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-5A		34	40	
		V <sub>GS</sub> =-1.8V , I <sub>D</sub> =-1.5A				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , I <sub>D</sub> =-250uA	-0.6	-0.8	-1.4	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient					mV/°C
1	Drain Source Lookage Current	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C				uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 12V$ , $V_{DS} = 0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-3A		10		S
Qg	Total Gate Charge (-4.5V)			10		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =-10V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6 <b>A</b> 5		1.5		nC
$Q_gd$	Gate-Drain Charge			3		
T <sub>d(on)</sub>	Turn-On Delay Time			30		ns
Tr		$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =6.0 $\Omega$	R <sub>G</sub> =6.0Ω	25		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		70		
T <sub>f</sub>	Fall Time			50		
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-10V , V <sub>GS</sub> =0V , f=1MHz		1210		
Coss	Output Capacitance			310		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			290		
ls	Continuous Source Current <sup>1,4</sup>				-7.0	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,4</sup> $V_G=V_D=0V$ , Force Current				-18.8	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1	V
t <sub>rr</sub>	Reverse Recovery Time			52		nS
Q <sub>rr</sub>	Reverse Recovery Charge	IF=-4A , dl/dt=100A/μs , T <sub>J</sub> =25°C		28		nC

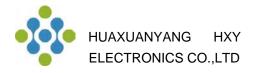
Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

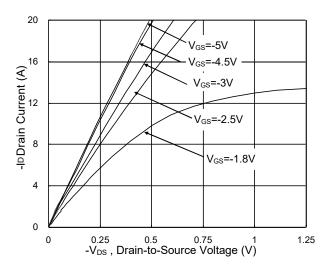
2.The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%$ 

3. The power dissipation is limited by 150°C junction temperature

4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications , should be limited by total power dissipation.



#### **Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

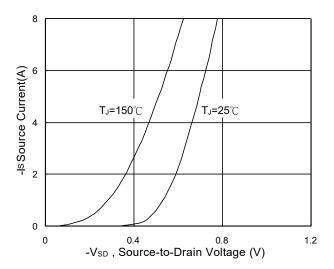


Fig.3 Forward Characteristics Of Reverse

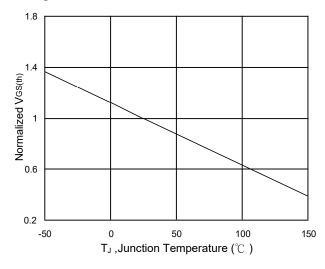


Fig.5 Normalized  $V_{\text{GS}(\text{th})}$  vs.  $T_{\text{J}}$ 

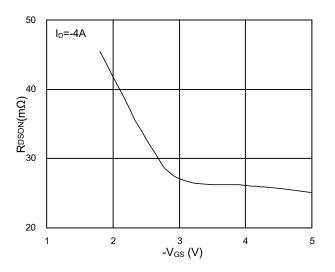


Fig.2 On-Resistance vs. Gate-Source

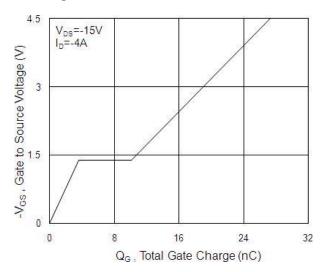


Fig.4 Gate-Charge Characteristics

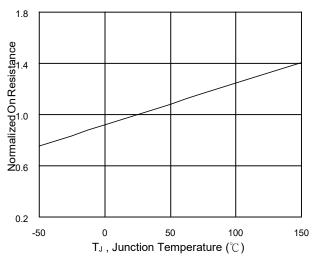
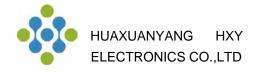


Fig.6 Normalized RDSON vs. TJ



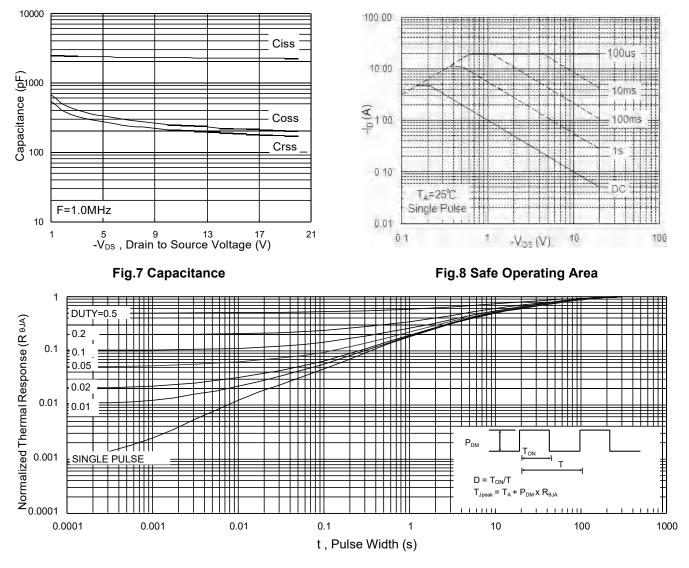


Fig.9 Normalized Maximum Transient Thermal Impedance

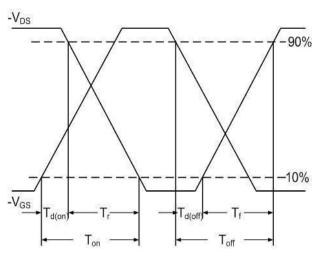
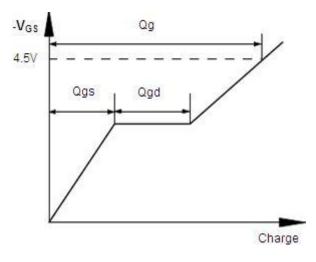


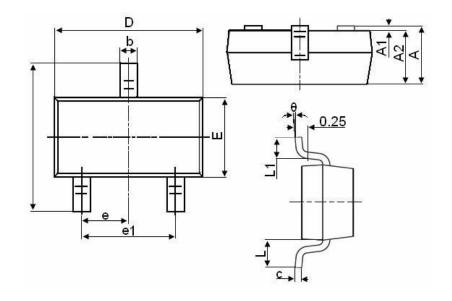
Fig.10 Switching Time Waveform







# SOT-23- 3LPackage Information



	Dimensions in Millimeters		
Symbol	MIN.	MAX.	
A	1.050	1.250	
A1	0.000	0.100	
A2	1.050	1.150	
b	0.300	0.500	
С	0.100	0.200	
D	2.800	3.000	
E	1.500	1.700	
E1	2.650	2.950	
е	0.950TYP		
e1	1.800	2.000	
L	0.550REF		
L1	0.300	0.600	
θ	0°	8°	



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